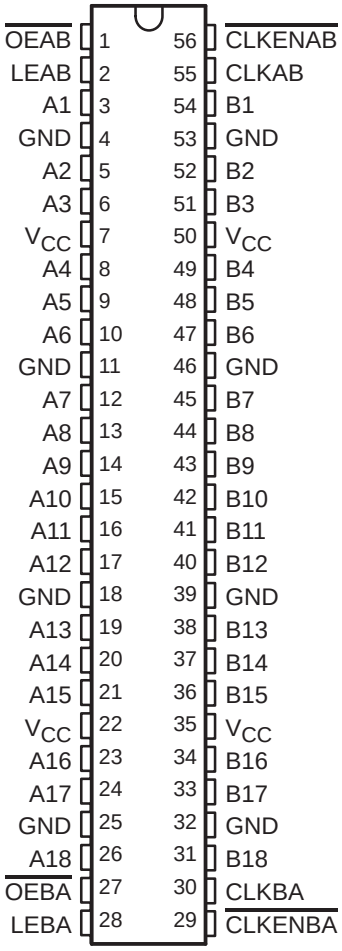
- **Members of the Texas Instruments *Widebus*™ Family**
- **State-of-the-Art *EPIC*-II*B*™ BiCMOS Design Significantly Reduces Power Dissipation**
- ***UBT*™ (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode**
- **Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17**
- **Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} = 5 V, T_A = 25°C**
- **Flow-Through Architecture Optimizes PCB Layout**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings**

SN54ABT16601 . . . WD PACKAGE
SN74ABT16601 . . . DGG OR DL PACKAGE
(TOP VIEW)



description

These 18-bit universal bus transceivers combine D-type latches and D-type flip-flops to allow data flow in transparent, latched, clocked, and clock-enabled modes.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock can be controlled by the clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB. Output enable $\overline{OEAB}$ is active low. When $\overline{OEAB}$ is low, the outputs are active. When $\overline{OEAB}$ is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B, but uses $\overline{OEBA}$, LEBA, CLKBA, and $\overline{CLKENBA}$.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16601 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT16601 is characterized for operation from –40°C to 85°C.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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FUNCTION TABLE†

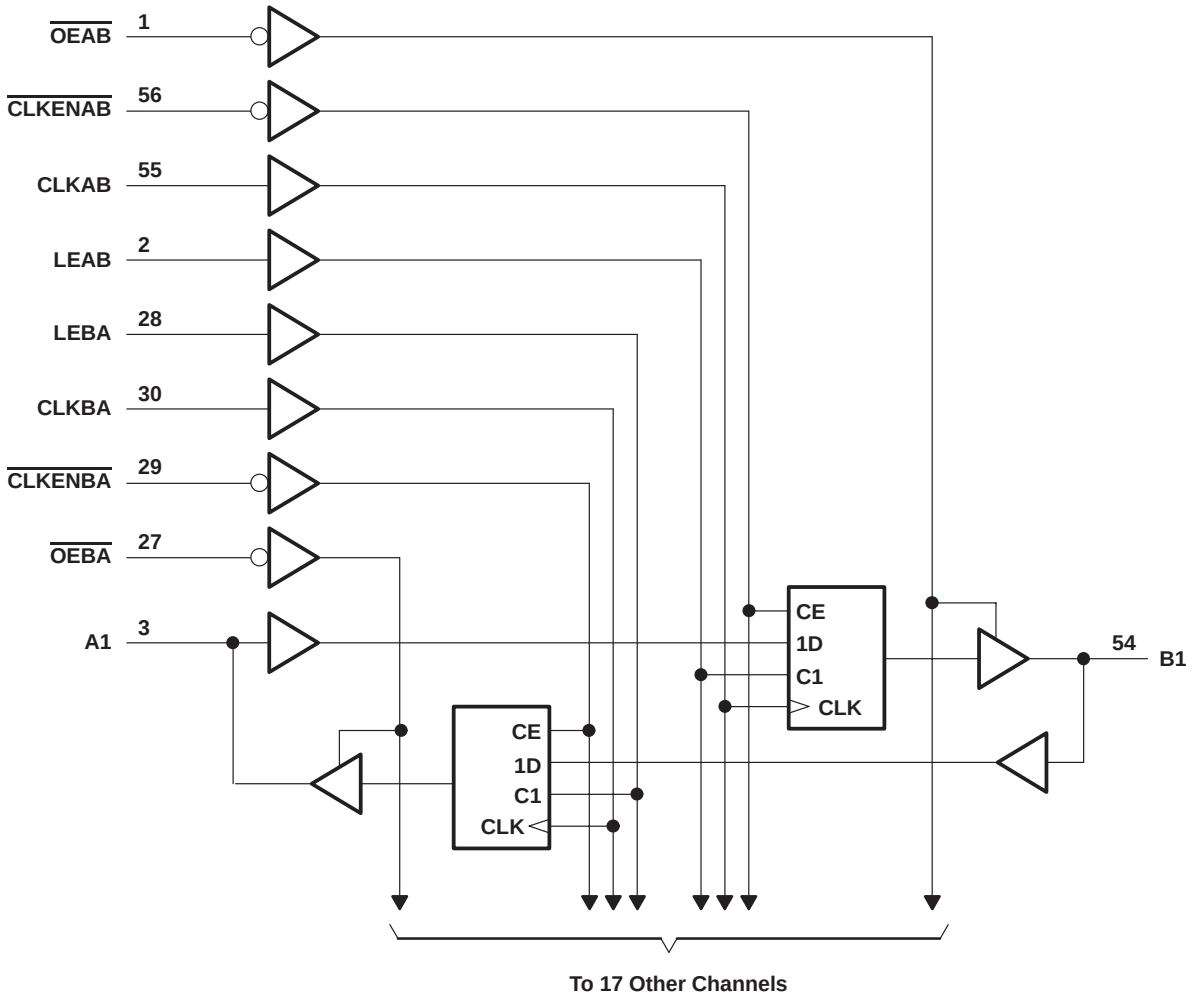
INPUTS					OUTPUT
$\overline{\text{CLKENAB}}$	$\overline{\text{OEAB}}$	LEAB	CLKAB	A	B
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B_0‡
H	L	L	X	X	B_0‡
L	L	L	↑	L	L
L	L	L	↑	H	H
L	L	L	L	X	B_0‡
L	L	L	H	X	B_0§

† A-to-B data flow is shown: B-to-A flow is similar but uses $\overline{\text{OEBA}}$, LEBA, CLKBA, and $\overline{\text{CLKENBA}}$.

‡ Output level before the indicated steady-state input conditions were established

§ Output level before the indicated steady-state input conditions were established, provided that CLKAB was low before LEAB went low

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (except I/O ports) (see Note 1) . . . . . –0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V_O . . . . . –0.5 V to 5.5 V
Current into any output in the low state, I_O: SN54ABT16601 . . . . . 96 mA
SN74ABT16601 . . . . . 128 mA
Input clamp current, I_{IK} (V_I < 0) . . . . . –18 mA
Output clamp current, I_{OK} (V_O < 0) . . . . . –50 mA
Package thermal impedance, θ_{JA} (see Note 2): DGG package . . . . . 81°C/W
DL package . . . . . 74°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

			SN54ABT16601		SN74ABT16601		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage		2		2		V
V_{IL}	Low-level input voltage			0.8		0.8	V
V_I	Input voltage		0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current			–24		–32	mA
I_{OL}	Low-level output current			48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
T_A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T_A = 25°C			SN54ABT16601		SN74ABT16601		UNIT
				MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA			–1.2		–1.2		–1.2	V
V_{OH}		V_{CC} = 4.5 V,	I_{OH} = –3 mA	2.5			2.5		2.5		V
		V_{CC} = 5 V,	I_{OH} = –3 mA	3			3		3		
		V_{CC} = 4.5 V	I_{OH} = –24 mA	2			2				
			I_{OH} = –32 mA	2*					2		
V_{OL}		V_{CC} = 4.5 V	I_{OL} = 48 mA			0.55		0.55			V
			I_{OL} = 64 mA			0.55*				0.55	
V_{hys}					100						mV
I_I	Control inputs	V_{CC} = 5.5 V,	V_I = V_{CC} or GND			±1		±1		±1	µA
	A or B ports					±20**		±100		±20	
I_{off}		V_{CC} = 0,	V_I or $V_O \le$ 4.5 V			±100				±100	µA
I_{CEX}		V_{CC} = 5.5 V, V_O = 5.5 V	Outputs high			50		50		50	µA
I_O‡		V_{CC} = 5.5 V,	V_O = 2.5 V	–50	–100	–180	–50	–180	–50	–180	mA
I_{OZH}§		V_{CC} = 5.5 V,	V_O = 2.7 V			10		10		10	µA
I_{OZL}§		V_{CC} = 5.5 V,	V_O = 0.5 V			–10		–10		–10	µA
I_{CC}	A or B ports	V_{CC} = 5.5 V, I_O = 0, V_I = V_{CC} or GND	Outputs high		1.9	3		2		3	mA
			Outputs low		28	36		35		36	
			Outputs disabled		1.6	3		2		3	
ΔI_{CC}¶		V_{CC} = 5.5 V, One input at 3.4 V, Other inputs at V_{CC} or GND				50				50	µA
								1.5			mA
C_i	Control inputs	V_I = 2.5 V or 0.5 V			3						pF
C_{io}	A or B ports	V_O = 2.5 V or 0.5 V			9						pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.
** This limit applies only to the SN74ABT16601.
† All typical values are at V_{CC} = 5 V.
‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
§ The parameters I_{OZH} and I_{OZL} include the input leakage current.
¶ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

				SN54ABT16601		SN74ABT16601		UNIT
				MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency			0	150	0	150	MHz
t_w	Pulse duration	LEAB or LEBA high		2.5		2.5		ns
		CLKAB or CLKBA high or low		3		3		
t_{su}	Setup time	A before CLKAB↑ or B before CLKBA↑		4.6		4		ns
		A before LEAB↓ or B before LEBA↓	CLK high	2.5		2.5		
			CLK low	1.3		1		
		$\overline{\text{CLKEN}}$ before CLK↑		2.9		2.5		
t_h	Hold time	A after CLKAB↑ or B after CLKBA↑		0.4		0		ns
		A after LEAB↓ or B after LEBA↓		2.8		2		
		$\overline{\text{CLKEN}}$ after CLK↑		0		0		

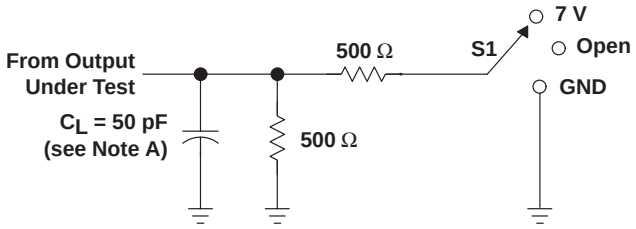
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54ABT16601					UNIT
			V_{CC} = 5 V, T_A = 25°C			MIN	MAX	
			MIN	TYP	MAX			
f_{max}			150	200		150		MHz
t_{PLH}	A or B	B or A	1.5	2.5	4.1	1	4.6	ns
t_{PHL}			1.5	3.4	4.7	1	5.1	
t_{PLH}	LEAB or LEBA	B or A	2	3.4	4.7	1	5.6	ns
t_{PHL}			2	3.7	5	1	5.5	
t_{PLH}	CLKAB or CLKBA	B or A	1.5	3.2	4.5	1	5.2	ns
t_{PHL}			1.5	3.2	4.4	1	5	
t_{PZH}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	B or A	2	4	5	1	5.7	ns
t_{PZL}			2	4.2	5.6	1	6	
t_{PHZ}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	B or A	2	4.5	5.8	1	6.8	ns
t_{PLZ}			1.5	3.4	5.3	1	6.3	

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

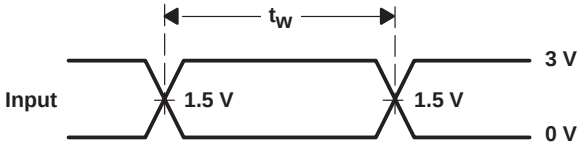
PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN74ABT16601					UNIT
			V_{CC} = 5 V, T_A = 25°C			MIN	MAX	
			MIN	TYP	MAX			
f_{max}			150	200		150		MHz
t_{PLH}	A or B	B or A	1.5	2.5	3.6	1.5	4	ns
t_{PHL}			1.5	3.4	4.7	1.5	4.9	
t_{PLH}	LEAB or LEBA	B or A	2	3.4	4.7	2	5	ns
t_{PHL}			2	3.7	5	2	5.2	
t_{PLH}	CLKAB or CLKBA	B or A	1.5	3.2	4.5	1.5	4.7	ns
t_{PHL}			1.5	3.2	4.4	1.5	4.6	
t_{PZH}	$\overline{OEAB}$ or $\overline{OEBA}$	B or A	2	4	5	2	5.5	ns
t_{PZL}			2	4.2	5.6	2	5.8	
t_{PHZ}	$\overline{OEAB}$ or $\overline{OEBA}$	B or A	2	4.5	5.4	2	6.2	ns
t_{PLZ}			1.5	3.4	4.7	1.5	5.4	

PARAMETER MEASUREMENT INFORMATION

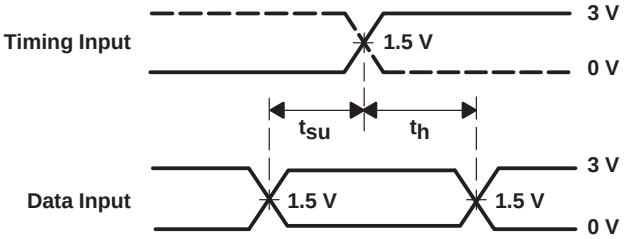


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

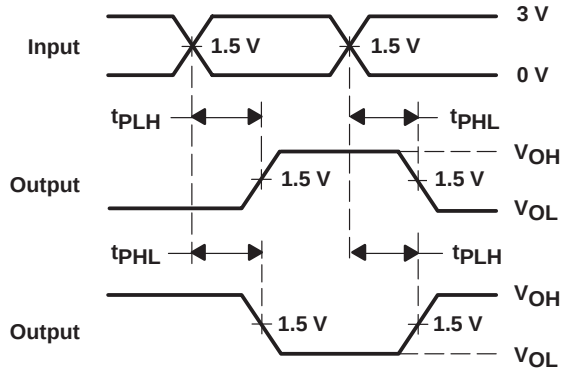
LOAD CIRCUIT



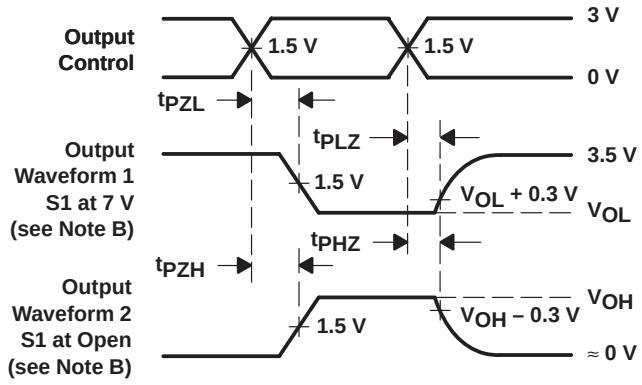
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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SN54ABT16601, 18-Bit Universal Bus Transceivers With 3-State Outputs

DEVICE STATUS: **ACTIVE**

PARAMETER NAME	SN54ABT16601	SN74ABT16601
Voltage Nodes (V)	5	5
Vcc range (V)	4.5 to 5.5	4.5 to 5.5
Input Level	TTL	TTL
Output Level	TTL	TTL
Output Drive (mA)		-32/64
No. of Outputs	18	18
Logic	True	True
Static Current		19.5
tpd max (ns)		4.9

FEATURES

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- Members of the Texas Instruments Widebus™ Family
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
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- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

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DESCRIPTION

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These 18-bit universal bus transceivers combine D-type latches and D-type flip-flops to allow data flow in transparent, latched, clocked, and clock-enabled modes.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock can be controlled by the clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB. Output enable $\overline{OEAB}$ is active low. When $\overline{OEAB}$ is low, the outputs are active. When $\overline{OEAB}$ is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B, but uses $\overline{OEBA}$, LEBA, CLKBA, and $\overline{CLKENBA}$.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Product Folder: SN54ABT16601, 18-Bit Universal Bus Transceivers With 3-State Outputs

The SN54ABT16601 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ABT16601 is characterized for operation from -40°C to 85°C.

TECHNICAL DOCUMENTS

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To view the following documents, Acrobat Reader 4.0 is required.
To download a document to your hard drive, right-click on the link and choose 'Save'.

DATASHEET

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Full datasheet in Acrobat PDF: sn54abt16601.pdf (122 KB,Rev.C) (Updated: 01/01/1997)

APPLICATION NOTES

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View Application Notes for Digital Logic

- Advanced BiCMOS Technology (ABT) Logic Characterization Information (Rev. B) (SCBA008B - Updated: 06/01/1997)
- Advanced BiCMOS Technology (ABT) Logic Enables Optimal System Design (Rev. A) (SCBA001A - Updated: 03/01/1997)
- Bus-Interface Devices With Output-Damping Resistors Or Reduced-Drive Outputs (Rev. A) (SCBA012A - Updated: 08/01/1997)
- Designing With Logic (Rev. C) (SDYA009C - Updated: 06/01/1997)
- Evaluation of Nickel/Palladium/Gold-Finished Surface-Mount Integrated Circuits (SZZA026 - Updated: 06/20/2001)
- Family of Curves Demonstrating Output Skews for Advanced BiCMOS Devices (Rev. A) (SCBA006A - Updated: 12/01/1996)
- Implications of Slow or Floating CMOS Inputs (Rev. C) (SCBA004C - Updated: 02/01/1998)
- Input and Output Characteristics of Digital Integrated Circuits (SDYA010 - Updated: 10/01/1996)
- Live Insertion (SDYA012 - Updated: 10/01/1996)
- Power-Up 3-State (PU3S) Circuits in TI Standard Logic Devices (SZZA033 - Updated: 05/10/2002)
- Quad Flatpack No-Lead Logic Packages (Rev. C) (SCBA017C - Updated: 11/22/2002)
- TI IBIS File Creation, Validation, and Distribution Processes (SZZA034 - Updated: 08/29/2002)
- Understanding Advanced Bus-Interface Products Design Guide (SCAA029, 253 KB - Updated: 05/01/1996)
- Understanding and Interpreting Texas Instruments Standard-Logic Products Data Sh (Rev. A) (SZZA036A - Updated: 02/27/2003)

MORE LITERATURE

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- Enhanced Plastic Portfolio Brochure (SGZB004, 387 KB - Updated: 08/19/2002)
- Logic Reference Guide (SCYB004, 1032 KB - Updated: 10/23/2001)
- MicroStar Junior BGA Design Summary (SCET004, 167 KB - Updated: 07/28/2000)
- Military Brief (SGYN138, 803 KB - Updated: 10/10/2000)
- Overview of IEEE Std 91-1984, Explanation of Logic Symbols Training Booklet (Rev. A) (SDYZ001A, 138 KB - Updated: 07/01/1996)
- Palladium Lead Finish User's Manual (SDYV001, 2041 KB - Updated: 11/01/1996)
- QML Class V Space Products Military Brief (Rev. A) (SGZN001A, 257 KB - Updated: 10/07/2002)

USER GUIDES

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- LOGIC Pocket Data Book (SCYD013, 4837 KB - Updated: 12/05/2002)

BLOCK DIAGRAMS

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- Electro-Optics
- Radar
- Target Detection Recognition

PRICING/AVAILABILITY/PKG

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Product Folder: SN54ABT16601, 18-Bit Universal Bus Transceivers With 3-State Outputs

DEVICE INFORMATION
Updated Daily

ORDERABLE DEVICE	STATUS	PACKAGE TYPE | PINS	TEMP (°C)	DSCC NUMBER	PRODUCT CONTENT	BUDGETARY PRICING QTY | $US	STD PACK QTY
5962-9467101QXA	ACTIVE	CFP (WD) | 56	-55 TO 125		View Contents	1KU | 24.14	1
SNJ54ABT16601WD	ACTIVE	CFP (WD) | 56	-55 TO 125	5962-9467101QXA	View Contents	1KU | 24.14	1

TI INVENTORY STATUS
As Of 09:00 AM GMT, 17 Apr 2003

IN STOCK	IN PROGRESS QTY | DATE	LEAD TIME
89*	>10k | 20 May	8 WKS
31*	>10k | 20 May	8 WKS

REPORTED DISTRIBUTOR INVENTORY
As Of 09:00 AM GMT, 17 Apr 2003

DISTRIBUTOR COMPANY | REGION	IN STOCK	PURCHASE
None Reported View Distributors		
None Reported View Distributors		

Table Data Updated on: 4/17/2003

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